Comparative Measurements between CRISP and LOLA-TDS at 13SMATCH.

HELMHOLTZ

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RESEARCH FOR GRAND CHALLENGES

Overview.

> Introduction CRISP

> Coherent Radiation Diagnostics

- Frequency domain
- Reconstruction into time domain

> Transverse Deflecting Structure

• Two Point Tomography

> Comparison at FLASH1

- Experimental setup
- Data analysis
- Measurements
- > Other and new CRISP stations
- > Summary



Introduction.

> Idea

- Reflective blazed gratings
- Strong polarization dependency in first and zeroth order
- Acts as low-pass and dispersive element simultaneously



- → Staging to increase band width
- → Broadband single shot spectra

→ 2-stage prototype by Hossein → 4-stage "user" spectrometer





Coherent Radiation Intensity SPectrometer.



Major design finished in 2010 Minor changes over last 8 years

> Specs

- in vacuum
- 2 grating sets
 - 4 40 um
 - 40 450 um
- focusing ring mirrors
- broadband pyro-electric sensors
- 120 channels
- fast readout on 1 us level





> Radiation emitted by electron bunch

- Synchrotron, Transition, Diffraction, ...
- Broadband spectrum, deep UV to far infrared / THz
- Small opening angle $\sim 1/\gamma$



→ Increase of radiated intensity by number of electron in bunch (N ~10^9)
 → Frequency dependent



fully incoherent (random interference)

fully coherent (constructive interference)

> Radiated spectral intensity

$$\frac{dU_{\rm coh}}{d\lambda} \approx \frac{dU_{\rm sing}}{d\lambda}$$

> Form factor == Fourier transform (transition between extreme cases)

$$F_{\text{long}}(k) = \int \rho_{\text{long}}(z) \, \exp(-\mathrm{i}k \cdot z) \, dz$$

 $F_{\text{long}}(k) = |F_{\text{long}}(k)| \exp(i\Phi(k))$

-> Get modulus of the form factor by measuring the spectral intensity



$$\cdot N^2 \cdot |F_{\text{long}}(\lambda)|^2$$

But phase information is lost!

> Example: Gaussian and rectangular profiles with <u>same</u> RMS lengths



→ Resolvable with a spectral measurement





> Example: I. Zagorodnov, FLASH beam dynamic simulations (www.desy.de/fel-beam/s2e/)



-> Form factor modulus is a unfamiliar quantity





Profile Reconstruction.

$$\rho(z) = \int F(k) \, \exp(\mathrm{i}k \cdot z) \, dk = \int |F(k)|$$

> Reconstruction out of the form factor modulus

 Mathematical statement in 1D M. H. Hayes, IEEE Transactions on Acoustics, Speech and Signal Processing, Vol. ASP-30, No. 2, April 1982

1. No unique retrieval of the phase information out of the form factor modulus. It is lost! 2. Reconstructed profiles are ambiguous and reflects only **one** potential solution

- General constraints

Insensitive on absolute arrival time Insensitive on time reversal (bunch tail \leftrightarrow head)



Phase information!

$|\exp(\mathrm{i}k\cdot z + \Phi(k))dk|$

Profile Reconstruction.

> Example: "Akuto"

E. J. Akutowicz, On the Determination of the Phase of a Fourier Integral, Trans. Amer. Math. Soc. 83, 179 (1956)

$$f_1(t) = e^{-\beta t}$$

$$f_2(t) = e^{-\beta t} \left(1 + \frac{4\beta^2 (1 - \cos(\alpha t))}{\alpha^2} - \frac{4\beta \sin(\alpha t)}{\alpha} \right)$$





 (αt)

 $|\mathcal{F}_1(\omega)| = |\mathcal{F}_2(\omega)| = \frac{1}{\sqrt{\beta^2 + \omega^2}}$

→ No chance to distinguish between these profiles by measuring |F|

Kramers-Kronig Reconstruction.

> Causal functions

- Profile / function $f \rightarrow f(t_0 < 0) = 0$
- → Explicit **analytical** relation
- > Adaption to |F|
 - KK phase by using

 $\ln F(\omega) = \ln |F(\omega)| + i \Phi(\omega)$

- Solving the principle value in complex plane R. Lai, U. Happek, and A.J. Sievers, Phys. Rev. E 50, R4294 (1994)
- |F| may have zeros in the upper half plane W. Blaschke, Berichte Math.-Phys., Kl. Sächs. Gesell. der Wiss. Leipzig, 67 (1915), 194-200
- Contribution of "Blaschke Phase" inaccessible

Perfect reconstruction only if the form factor has no complex zeros



$$\Re(\tilde{f}(\omega_0)) = \frac{1}{\pi} \int \frac{\Im(\tilde{f}(\omega))}{\omega - \omega_0} d\omega$$
$$\Im(\tilde{f}(\omega_0)) = -\frac{1}{\pi} \int \frac{\Re(\tilde{f}(\omega))}{\omega - \omega_0} d\omega$$





Kramers-Kronig Reconstruction

> Examples









Iterative Reconstruction.

> Gerchberg-Saxton algorithm





> Applied constrains

- Charge density > 0
- Bunch profile is localized

→ Run multiple times with different starting parameters …



R.W. Gerchberg and W.O. Saxton, "A practical algorithm for the determination of phase from image and diffraction plane pictures", Optik 35, 227 (1972)

 $\mathcal{G}'_n(\omega) = F(\omega) \exp(i\varphi_n(\omega))$

> Stop criterion

- Fix number of iterations
- Convergence of profile

Iterative Reconstruction.

> Example: Convergence



> Example: "Akuto" and Gaussian Profile





mean profile + error band

Shift Motivation.

"Comparative Measurements between CRISP and LOLA-TDS at 13SMATCH"

- Test reconstruction methods on real FLASH beam profiles
- → Reliable bunch profile measurements by CRISP?
- → Measure shortest bunches down to 50 fs rms



Transverse Deflecting Structure.



Offset in zero-crossing

$$y = y_0 + S \cdot z$$

Streak given by optics and TDS

$$S = R_{34}(s, s_0) \, k = \sqrt{\beta_y(s)\beta_y(s_0)} \, \sin \Delta \Psi_y(s, s_0) \, \frac{2\pi}{c^2} \, \frac{\epsilon}{p}$$

Resolution given by bunch properties

$$\mathcal{R}_z = \frac{\sigma_{y0}}{S} = \sqrt{\frac{\epsilon_{n,y}}{\beta_y(s_0)}} \frac{1}{\sin \Delta \Psi_y(s,s_0)} \frac{mc^3}{2\pi e} \frac{\sqrt{\gamma - 1/\gamma}}{V_0 f}$$



 $\frac{e}{p}V_0f$

→ LOLA-TDS available at FLASH

Two Point Tomography.

> Intrinsic centroid correlation <y>(z)

 $f_{\pm}(z) = \langle y \rangle_{\pm}(z) = f_0(z) + S_{\pm} z$





Idea by Hendrik Loos

• Accumulated charge $q_+(y) = \int_{-\infty}^{y} \rho_+(y^*) \, dy^*$

$$q_-(y) = \int_y^\infty \rho_-(y^*) \, dy^*$$

Map

$$z(q) = \frac{y_+(q) - y_-(q)}{S_+ - S_-}$$

Reconstruction of correlation and profile

$$\frac{y_{-}(q) - S_{-} y_{+}(q)}{S_{+} - S_{-}} \qquad \qquad \rho_{z,r}(z) = \frac{d}{dz} q(z)$$

Two Point Tomography.

> Example: I. Zagorodnov



TDS measurement + Reconstruction





Successful with sufficient streak

CRISP@FLASH.

> CRISP@202m (@FL1)

- inside tunnel
- delays: BLM masking, kicker, screen, detectors, ...
- exchange complete spectrometer in 2015



- beamline to external lab 28g
- commissioning of the 1st CRISP
- first comparisons with LOLA-TDS



Experimental Setup SDUMP/SMATCH.







Designed to compare both diagnostics







Experimental Setup SDUMP/SMATCH.

> SDUMP special optics

- Based on FLASH1 theory optics
- Streak in y:
- $\beta_{\text{TDS}} = 41 \text{ m},$ $\beta_{SCR} = 4 \text{ m},$ ψ ~ π/2 • Energy x: $\beta = 0.54 \text{ m},$ $\eta = 0.77 \text{ m}$
- Works for 13SMATCH as well



(for 20 MV and 1 GeV/c, 1 um·rad)

- S = 15
- $R_z = 3 \text{ um (rms)}$
- $R_{\delta} = 2 \times 10^{-4}$ (rms, dominated by TDS)



80

→ Excellent time resolution (matched beam in SFUND needed)







Machine Setup.

> Check list: Machine

- Virtual cathode
- Phase scans
- Set minimum energy spread downstream BC2
- Match in DBC2 (4 screen method)
- Set minimum energy spread downstream BC3
- Close dispersion in dogleg
- Match in SFUND (4 screen method)
- Set special SDUMP optics

> Check list: Measurement

- Set compression (sum voltage control, intuitive)
- Measure longitudinal phase space with TDS
- Switch to 13SMATCH (dark current tuning)
- Measure spectra with CRISP
- Switch back to 6SDUMP
- Set new compression ...

Spent a lot of time to prepare the machine



x Optics in SFUND

- Small beam sizes on screens
- Weird beam shapes
- Matching somehow random

x Switching to 130TRSMATCH

- Upstream killer steerers
- Attention to DC in undulators

TDS Measurement.

> Data taking for both zero-crossings

- Time calibrations
- Single image
- 20 images

> Time calibration analysis (update)

- Based on energy slices
- Better understanding of resolution





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> Image analysis

- Correct for center of mass shifts
- Scale all profiles to the mean bunch length
- Averaging profiles
 - ... potentially wash out micro-structures





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> Two point tomography

- Most likely profile
- Centroid shift





Tomography - 2018-05-14T053553 - SDUMP



CRISP Measurement.

> Data taken

- 200 shots
- 2 grating sets

> Measure form factor

- Average of all shots (for now)
- Well calibrated device (source → electronics)
- Characterization by response (infinitesimal short bunch)
- ADC signal \rightarrow form factor

$$|F_l| = \left(\frac{adc \, signal[V]}{charge[nC]^2 \cdot response[V]}\right)^{1/2}$$





CRISP Measurement.

> Data taken • 200 shots 2 grating sets > Measure form factor • Average of all shots (for now) • Well calibrated device (source → electronics) Characterization by response (infinitesimal short bunch) • ADC signal → form factor

$$|F_l| = \left(\frac{adc \, signal[V]}{charge[nC]^2 \cdot response[V]}\right)^{1/2}$$

> Analyse form factor

- Errors statistical
- Sensitivity by ADC noise level





CRISP@FL2.

> Delays

• Solved:

new uTCA electronics over-heating of electronics wrong THz beamline focussing mirror no off-axis screen

• Missing:

lead shielding for parallel operation

> Status

- Beamline and spectrometer aligned (laser- and ebeam-based)
- First bunch spectra by Tanish Satoor (summer student 2017)
- Kicker characterization
- Problems
 - a.) extremely fluctuating signal on alignment pyros
 - b.) other time consuming projects

Station is alive

Next measurements planned in Feb







CRISP@EuXFEL

> Setup

- In XTL at 1934 m (17.5 GeV = final energy)
- Non-invasive diffraction radiator

> Goals

- Monitoring all bunches simultaneously
- Feedback on pulse-train bunch profiles

> Status

- Installed
- Technical commissioned
- First spectra taken
- First cross-checks with TDS
- DOOCS server by O. Hensler



→ PhD student Nils Lockmann with C. Gerth and J. Röver (MSK)







- > CRISP very well understood and characterized during the past years
- > Comparisons with TDS show impressive agreements
- > Stations at FLASH2 and EuXFEL
- > Seamless integration into DOOCS has been started ...



... CRISP as a regular bunch profiles monitor

> Further reading

- PhD Thesis, **DESY-THESIS-2012-052**
- 'CRISP', NIMA 665 (2011) 40-47
- 'Reconstruction', DESY 18-027